

IRFBE30LPBF-VB Datasheet

Power MOSFET

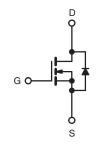
PRODUCT SUMMARY					
V _{DS} (V)	850				
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	2.7			
Q _g (Max.) (nC)	78				
Q _{gs} (nC)	9.6				
Q _{gd} (nC)	45				
Configuration	Single				

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC



Top View



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ($T_c = 25 \degree C$, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	850	N	
Gate-Source Voltage			V _{GS}	± 20	V	
Continuous Drain Current	V =======V	T _C = 25 °C		4.1		
	V _{GS} at 10 V	T _C = 100 °C	ID	2.6	А	
Pulsed Drain Current ^a			I _{DM}	16		
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	260	mJ	
Avalanche Current ^a			I _{AR}	4.1	А	
Repetitive Avalanche Energy ^a			E _{AR}	13	mJ	
Maximum Power Dissipation $T_{C} = 25 \text{ °C}$			PD	125	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	- °C	
Soldering Recommendations (Peak Temperature) for 10 s				300 ^d		
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 29 mH, $R_g = 25 \Omega$, $I_{AS} = 4.1 \text{ A}$ (see fig. 12). c. $I_{SD} \le 4.1 \text{ A}$, dl/dt $\le 100 \text{ A/}\mu\text{s}$, $V_{DD} \le 600 \text{ V}$, $T_J \le 150 \text{ °C}$. d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	-	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	1.0		

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							•
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA		850	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference	e to 25 °C, I _D = 1 mA	-	0.90	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	V _{DS} = V _{GS} , I _D = 250 μA		-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 20 V		-	± 100	nA
		V _{DS} = 800 V, V _{GS} = 0 V		-	-	100	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 640 V	∕, V _{GS} = 0 V, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.5 A ^b	-	2.7	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 100 V, I _D = 2.5 A		2.5	-	-	S
Dynamic						•	•
Input Capacitance	C _{iss}		$V_{GS} = 0 V,$	-	1300	-	pF
Output Capacitance	C _{oss}		$V_{DS} = 25 V,$	-	310	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.	.0 MHz, see fig. 5	-	190	-	
Total Gate Charge	Qg			-	-	78	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 V$ $I_D = 4.1 A, V_{DS} = 400 V,$ see fig. 6 and 13 ^b		-	9.6	nC
Gate-Drain Charge	Q _{gd}			-	-	45	1
Turn-On Delay Time	t _{d(on)}				12	-	- ns
Rise Time	t _r	$\label{eq:V_DD} \begin{array}{l} V_{DD} = 400 \text{ V}, \text{ I}_{D} = 4.1 \text{ A}, \\ R_g = 12 \ \Omega, \ R_D = 95 \ \Omega, \ \text{see fig. } 10^{\text{b}} \end{array}$		-	33	-	
Turn-Off Delay Time	t _{d(off)}			-	82	-	
Fall Time	t _f				30	-	
Internal Drain Inductance	L _D		Between lead, 6 mm (0.25") from		4.5	-	
Internal Source Inductance	L _S	package and center of die contact		-	7.5	-	nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4.1	Α
Pulsed Diode Forward Current ^a	I _{SM}			-	-	16	
Body Diode Voltage	V_{SD}	$T_J = 25 \ ^{\circ}C, \ I_S = 4.1 \ A, \ V_{GS} = 0 \ V^b$		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = 4.1 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}^b$		-	480	720	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	1.8	2.7	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L				L _D)	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

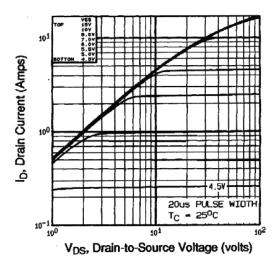


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

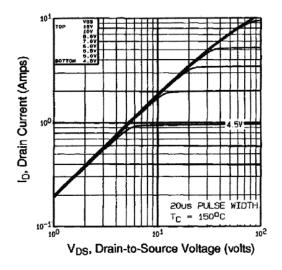


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

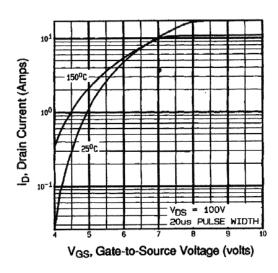


Fig. 3 - Typical Transfer Characteristics

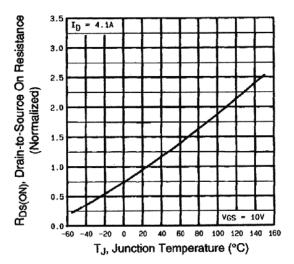


Fig. 4 - Normalized On-Resistance vs. Temperature



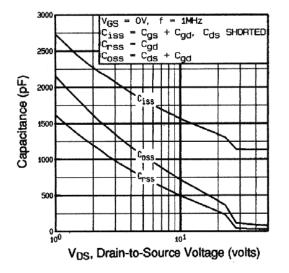


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

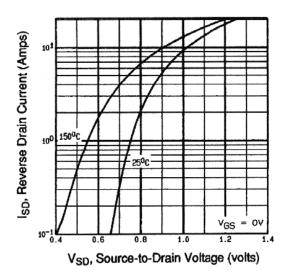


Fig. 7 - Typical Source-Drain Diode Forward Voltage

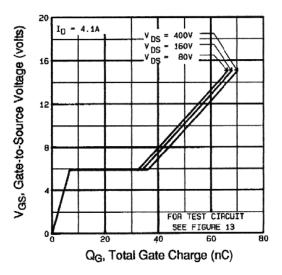
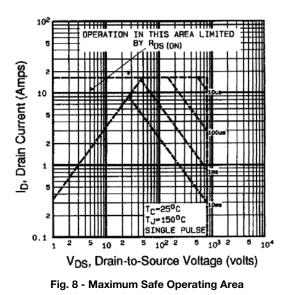


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





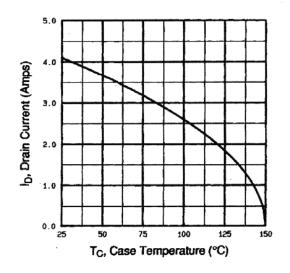


Fig. 9 - Maximum Drain Current vs. Case Temperature

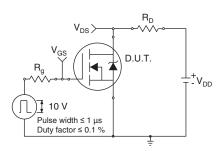


Fig. 10a - Switching Time Test Circuit

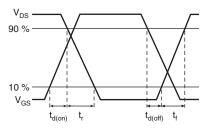
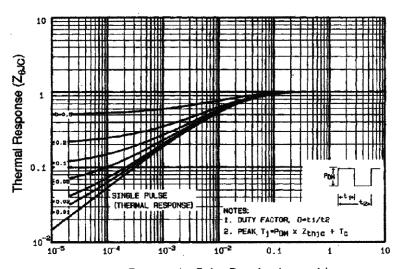


Fig. 10b - Switching Time Waveforms





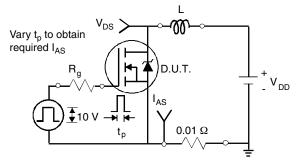


Fig. 12a - Unclamped Inductive Test Circuit

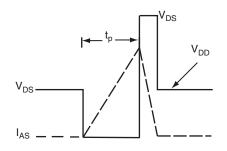


Fig. 12b - Unclamped Inductive Waveforms



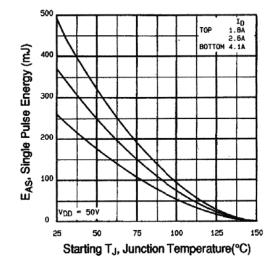


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

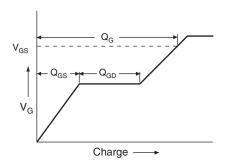


Fig. 13a - Maximum Avalanche Energy vs. Drain Current

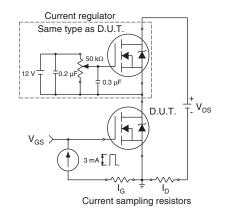
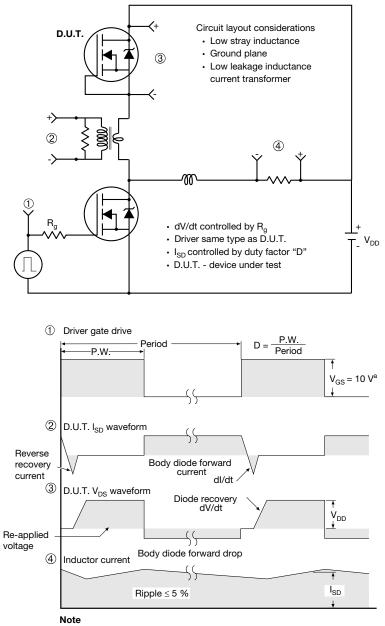


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



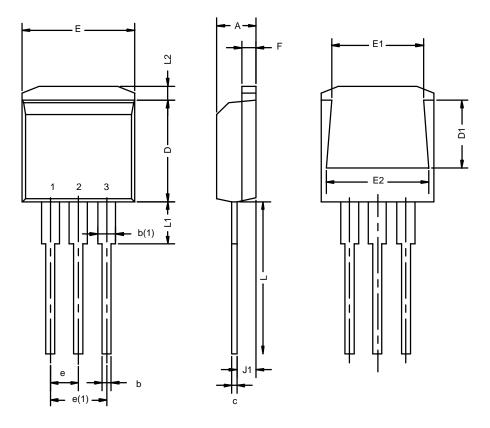
a. $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel

IRFBE30LPBF-VB



TO-262: 3-LEAD



	MILLIM	ETERS*	INCHES		
Dim	Min	Max	Min	Max	
Α	4.32	4.70	0.170	0.185	
b	0.64	1.00	0.025	0.039	
b(1)	1.14	1.40	0.045	0.055	
С	0.36	0.50	0.014	0.020	
D	8.64	9.65	0.340	0.380	
D1	5.59	6.10	0.220	0.240	
е	2.41	2.67	0.095	0.105	
e(1)	4.95	5.33	0.195	0.210	
E	10.03	10.41	0.395	0.410	
E1	7.87	8.64	0.310	0.340	
E2	9.02	9.53	0.355	0.375	
F	1.14	1.40	0.045	0.055	
J1	2.41	2.79	0.095	0.110	
L	13.08	14.22	0.515	0.560	
L1	-	3.81	-	0.150	
L2	1.02	1.40	0.040	0.055	
ECN: T-02234—Rev. C, 14-Oct-02 DWG: 5855					

*Use millimeters as the primary measurement



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